

Semiconductor physics: basics

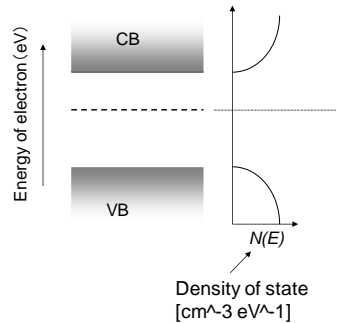
Google → Power Kyutech

Pw = ISPSD

Diagram of theories

Solid-state physics

Band structure



Fermi-Dirac distribution,
Density of state and electron density

Semiconductor (Device) physics

Carrier concentration

$$n = n_i \cdot e^{(E_F - E_i)/kT}$$

$$p = n_i \cdot e^{(E_i - E_F)/kT}$$

Thermal equilibrium condition

Boltzmann
Approximation

Energy \rightarrow
Potential

Semiconductor Device Design

Carrier and potential (Voltage)

$$n = n_i \cdot e^{\frac{q}{kT}(\phi - \phi_i)}$$

$$p = n_i \cdot e^{\frac{q}{kT}(\phi_i - \phi)}$$

Drift – Diffusion Model

$$J_n = -q \mu_n n \frac{d\phi}{dx} + q D_n \frac{dn}{dx}$$

$$J_p = -q \mu_p p \frac{d\phi}{dx} - q D_p \frac{dp}{dx}$$

Boltzmann
Distribution
Ideal gas

Models in
Other
Fields

Current continuity equation

Gauss' divergence theorem

Poisson Eq

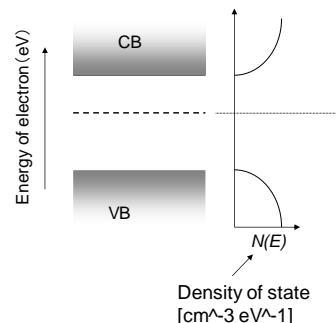
Diagram of theories (today)

Solid-state physics

Semiconductor (Device) physics

Semiconductor Device Design

Band structure



Fermi-Dirac distribution,
Density of state and electron density

Boltzmann
Approximation

Carrier and potential (Voltage)

$$n = n_i \cdot e^{(E_F - E_i)/kT}$$

$$p = n_i \cdot e^{(E_i - E_F)/kT}$$

Energy \rightarrow
Potential

$$n = n_i \cdot e^{\frac{q}{kT}(\phi - \phi_i)}$$

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Drift – Diffusion Model

$$J_n = -q \mu_n n \frac{d\phi}{dx} + q D_n \frac{dn}{dx}$$

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Models in
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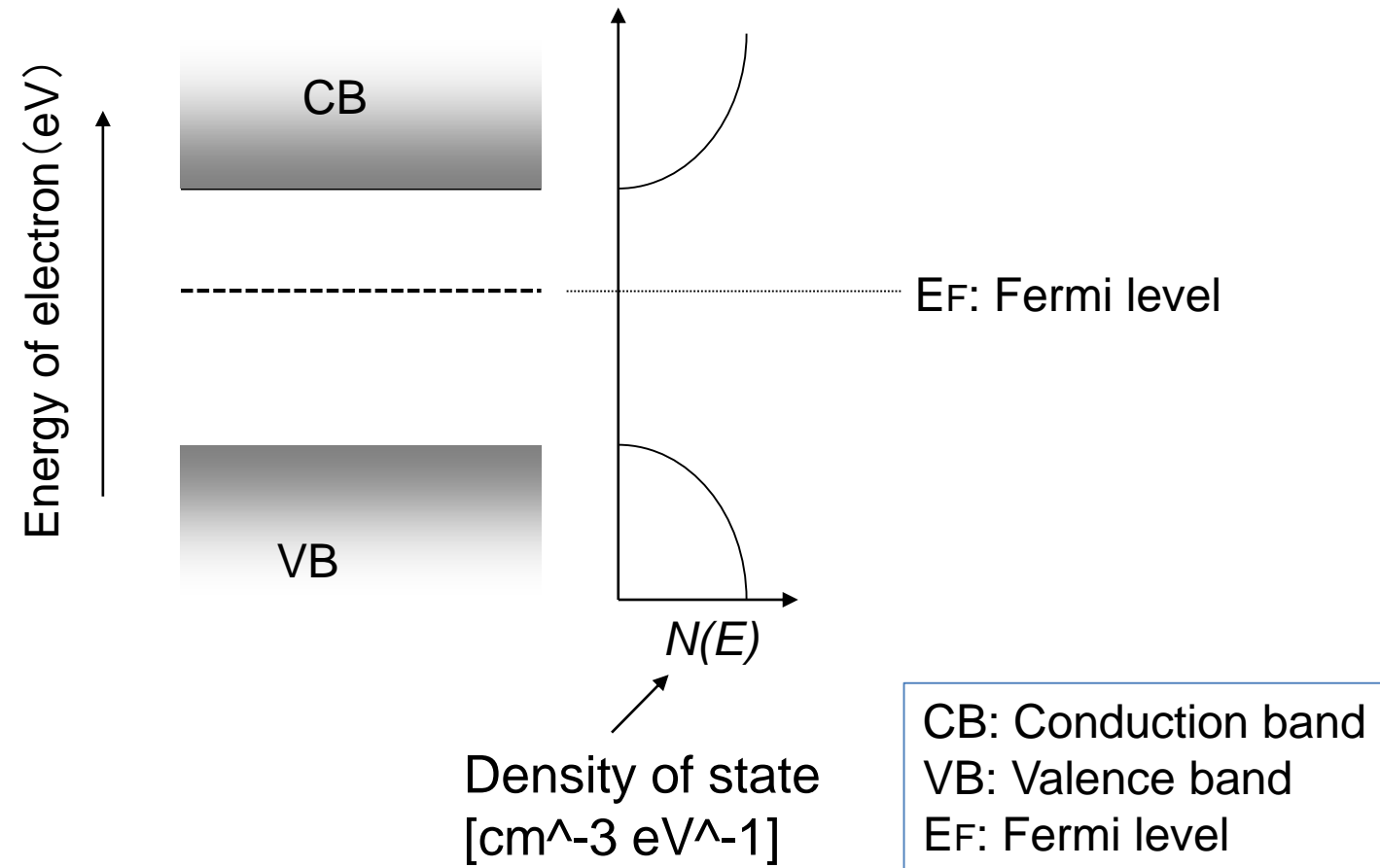
Current continuity equation

Gauss' divergence theorem

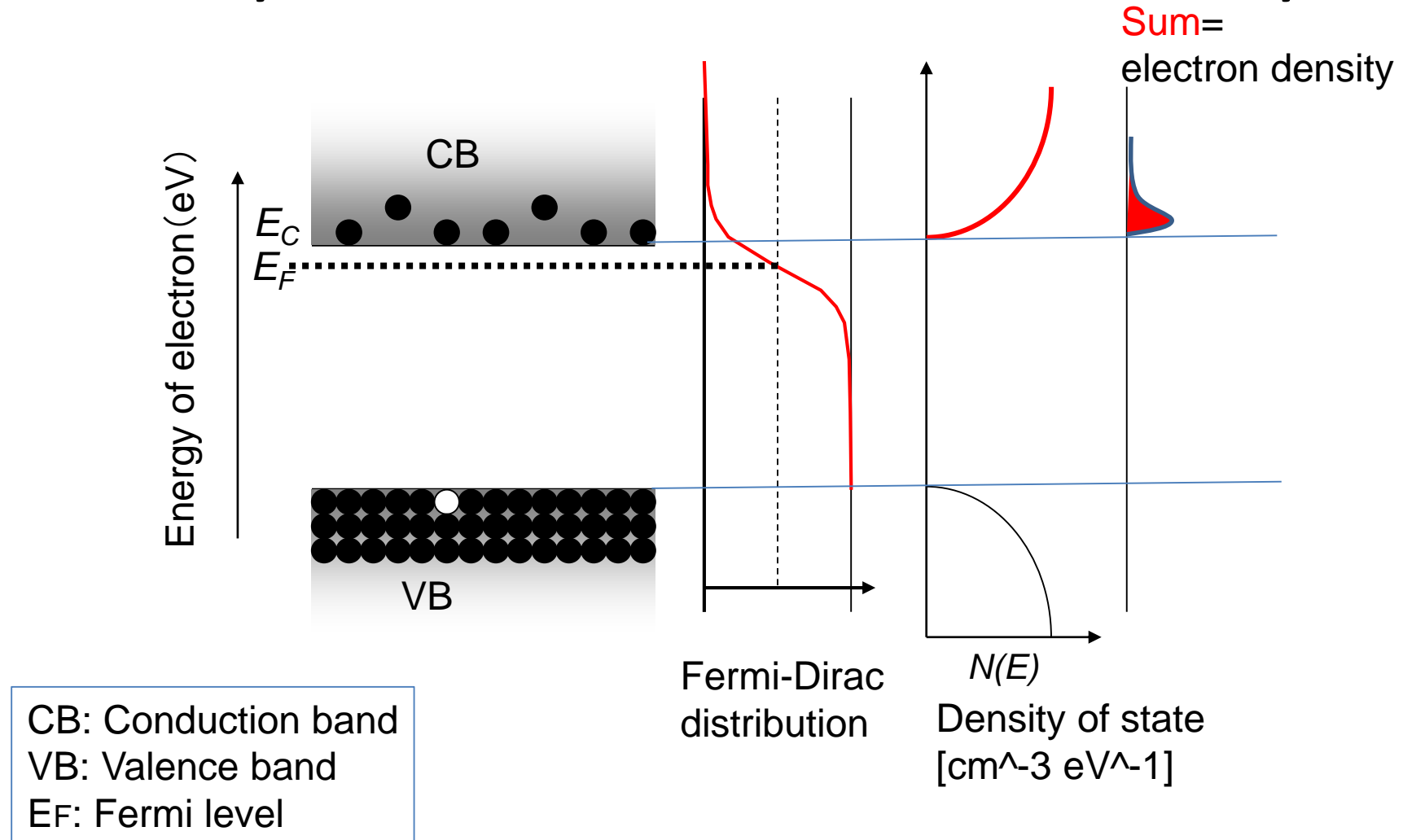
Poisson Eq

Semiconductor physics basics

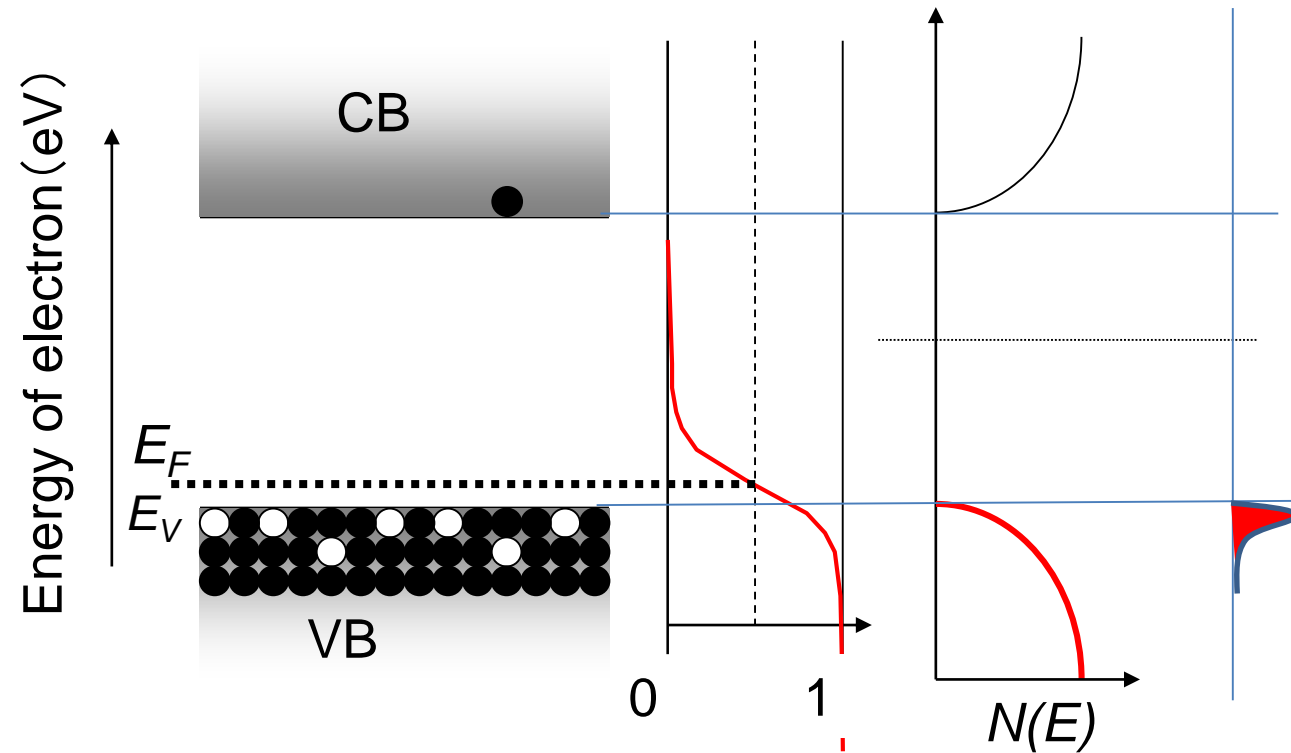
Band gap of semiconductor



Fermi-Dirac distribution, Density of state and electron density



Fermi-Dirac distribution, Density of state and hole density

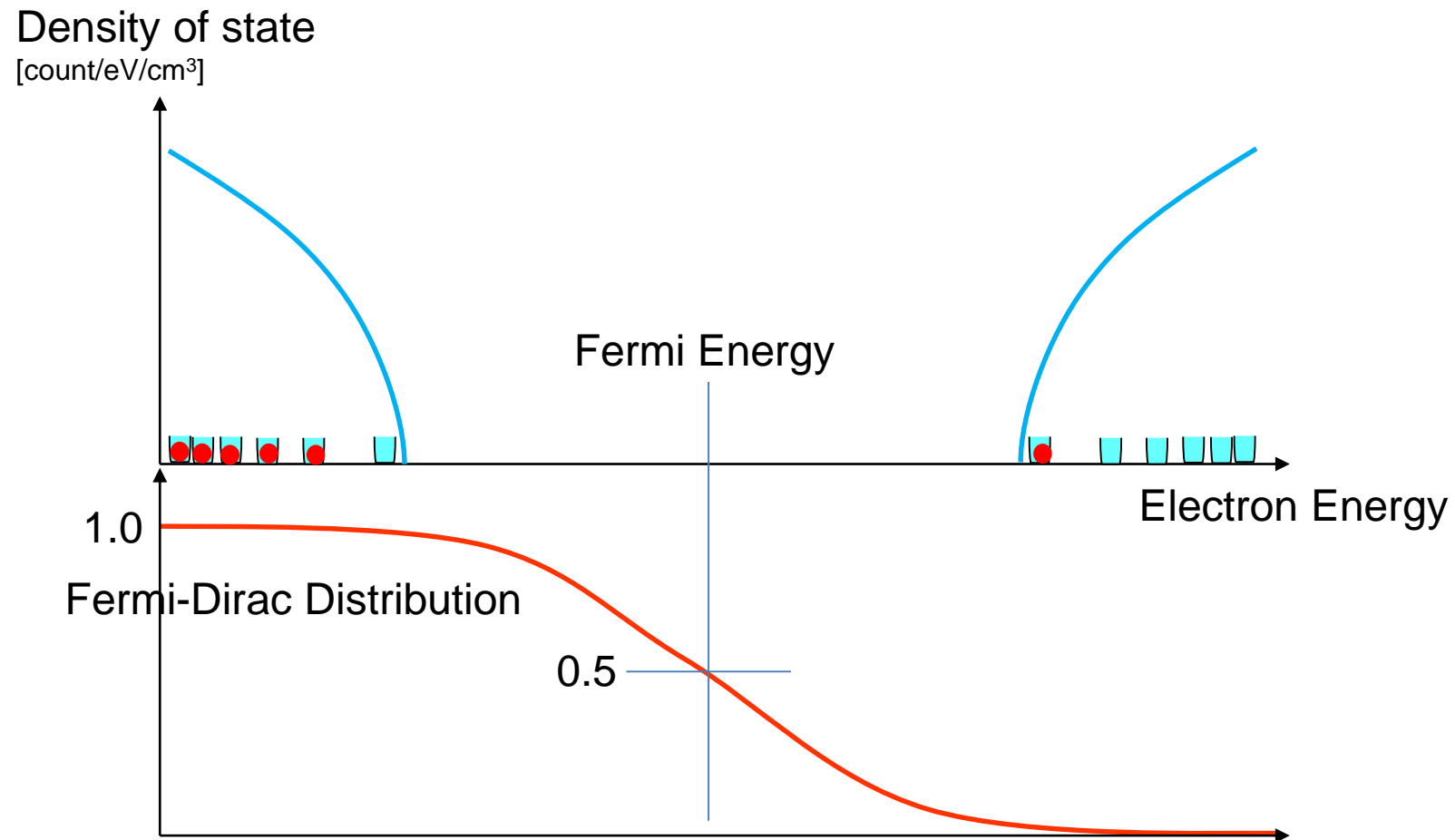


CB: Conduction band
VB: Valence band
 E_F : Fermi level

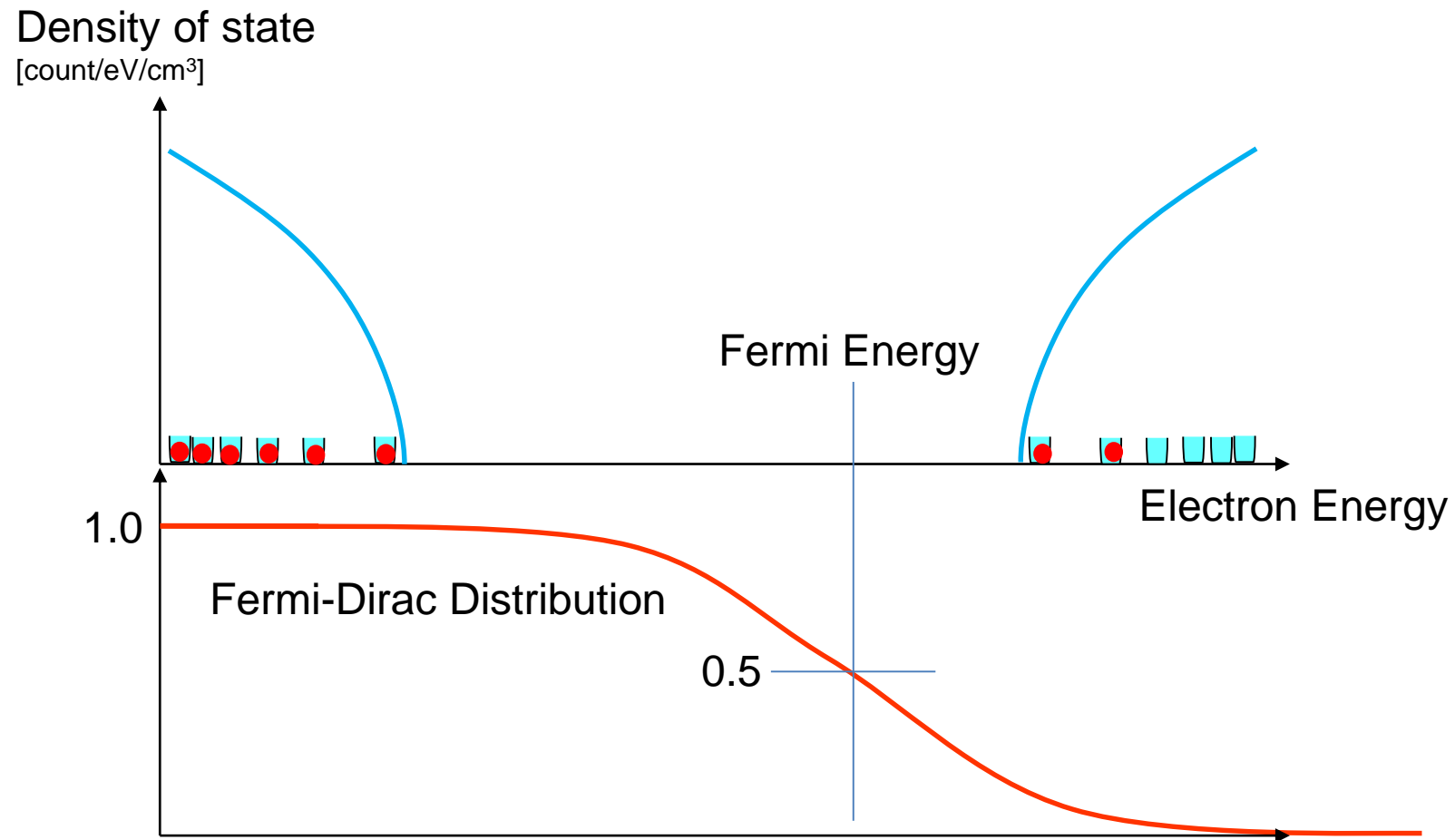
Fermi-Dirac
distribution

Density of state
[cm⁻³ eV⁻¹]

Remark: Density of state and Fermi energy



Remark: Density of state and Fermi energy



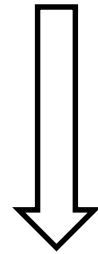
Boltzmann Approximation

Electron

Fermi-Dirac
distribution

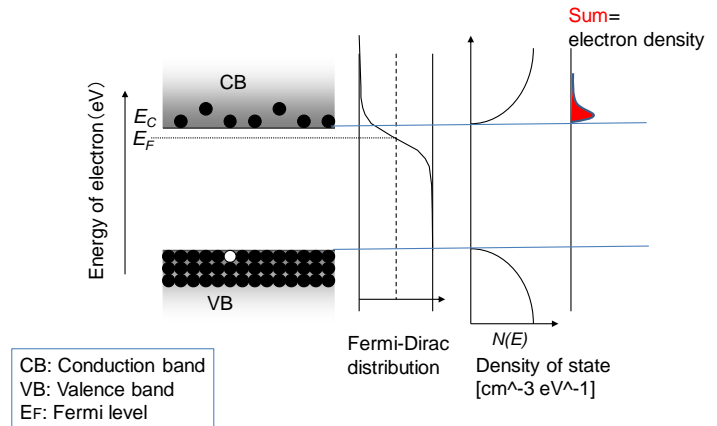
Density of
state

$$n = \int_{E_c}^{\infty} \frac{1}{1 + e^{(E - E_F)/kT}} N(E) dE$$



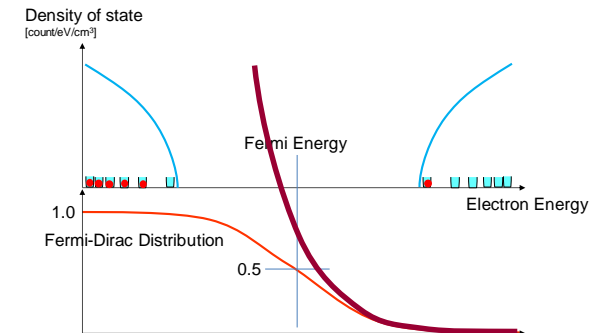
$$\frac{1}{1 + e^{(E - E_F)/kT}} \approx e^{-(E - E_F)/kT} \quad \gg 1$$

$$n = \int_{E_F}^{\infty} e^{-(E - E_F)/kT} N(E) dE$$



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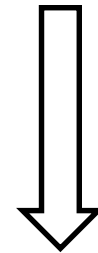
Boltzmann Approximation

Hole

Fermi-Dirac
distribution

Density of
state

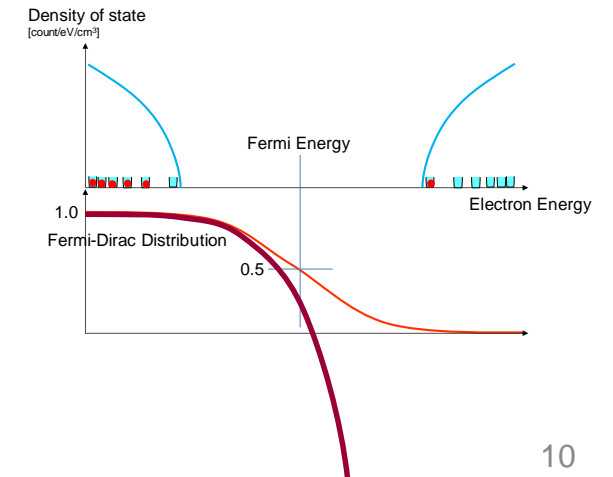
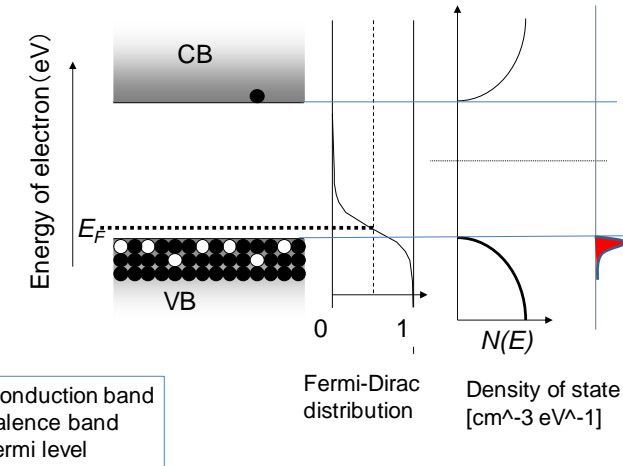
$$p = \int_{-\infty}^{E_V} \left\{ 1 - \frac{1}{1 + e^{(E - E_F)/kT}} \right\} N(E) dE$$



$$1 - \frac{1}{1 + e^{(E - E_F)/kT}} = \frac{e^{(E - E_F)/kT}}{1 + e^{(E - E_F)/kT}} \approx e^{(E - E_F)/kT}$$

$\ll 1$

$$p = \int_{-\infty}^{E_F} e^{(E - E_F)/kT} N(E) dE$$



Boltzmann Approximation (Thermal Equilibrium)

Electron

$$n(E_F) = \int_{E_F}^{\infty} e^{-(E-E_F)/kT} N(E) dE$$

Hole

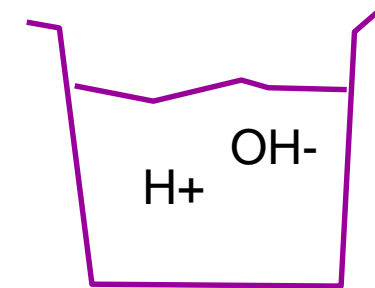
$$p(E_F) = \int_{-\infty}^{E_F} e^{(E-E_F)/kT} N(E) dE$$

$$\underline{p(E_F) \times n(E_F)} = \int_{E_F}^{\infty} e^{-(E-E_F)/kT} N(E) dE \times \int_{-\infty}^{E_F} e^{(E-E_F)/kT} N(E) dE$$

= Constant for any E_F

Define **intrinsic carrier density** n_i as,

$$n_i = \sqrt{p(E_F) \times n(E_F)} \longrightarrow \boxed{p \cdot n = n_i^2}$$



$$[H^+] \times [OH^-] = 1 \times 10^{-14} (\text{mol/L})^2$$

Boltzmann Approximation (Thermal Equilibrium)

Ideal semiconductor crystal under thermal equilibrium

→ electric field =0

→ No space charge

→ $n = p$ is satisfied in the crystal and they are equal to n_i

Intrinsic Fermi energy E_i is defined as Fermi energy satisfying,

$$n(E_i) = p(E_i) = n_i$$

$$n = n_i \cdot e^{(E_F - E_i)/kT} \quad p = n_i \cdot e^{(E_i - E_F)/kT}$$

Boltzmann Approximation to carrier density and potential

$$n = n_i \cdot e^{(E_F - E_i)/kT} \quad p = n_i \cdot e^{(E_i - E_F)/kT}$$

Potential $\varphi = -\frac{E_i}{q}$

Fermi Potential $\phi = -\frac{E_F}{q}$

$$n = n_i \cdot e^{\frac{q}{kT}(\phi - \varphi)} \quad p = n_i \cdot e^{\frac{q}{kT}(\varphi - \phi)}$$

Good bye “Band theory”, “electron energy”, Density of state, Fermi-Dirac distribution!!

Drift velocity

Electric field (V/cm)
↓

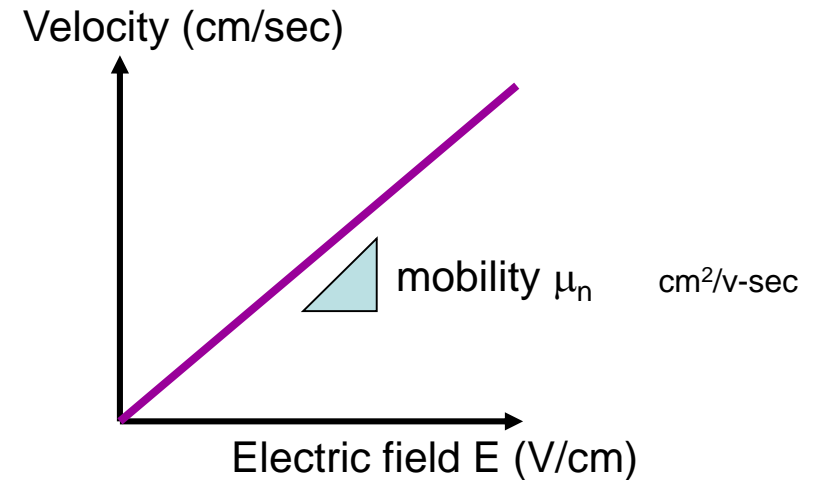
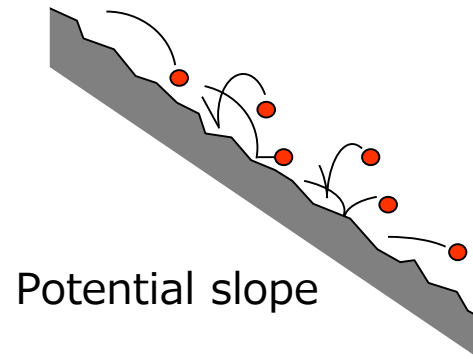
Velocity of electron $v_n = -\mu_n \cdot E$

Velocity of hole $v_p = \mu_p \cdot E$

Electric field
↓

Potential[V]
↓

$$E = -\frac{d\phi}{dx}$$

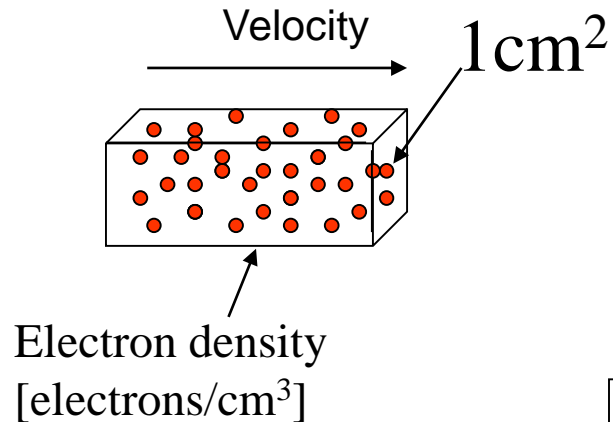


Drift current density

Flux: count/cm²*sec

Drift current = Electron charge X Drift carrier flux

Drift carrier flux [carriers/cm²/sec]
= Carrier density [carriers/cm³] X velocity[cm/sec]



Electron drift current density[A/cm²]

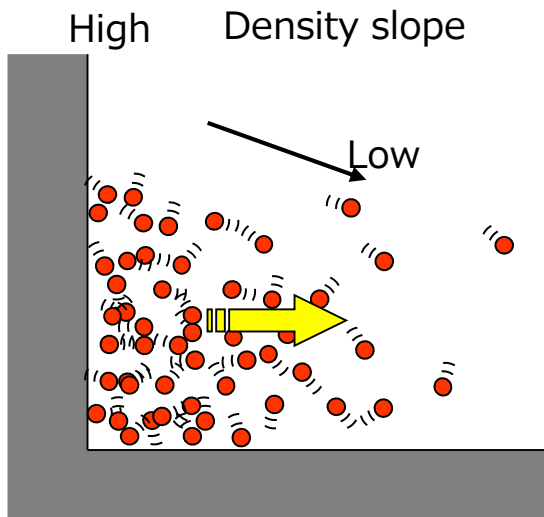
$$J_n = -qv_n n \longrightarrow J_n = q \mu_n n E$$

Hole drift current density[A/cm²]

$$J_p = qv_p p \longrightarrow J_p = q \mu_p p E$$

Diffusion current density

Diffusion current: Current by carrier diffusion with density difference



Electron diffusion flux $= -D_n \frac{dn}{dx}$

Electron diffusion current density

$$J_n = qD_n \frac{dn}{dx}$$

Hole diffusion flux $= -D_p \frac{dp}{dx}$

Hole diffusion current density

$$J_p = -qD_p \frac{dp}{dx}$$

Drift-diffusion model

= Current equation

Electron and hole current density (Drift + diffusion)

$$J_n = -q \mu_n n \frac{d\phi}{dx} + q D_n \frac{dn}{dx}$$

$$J_p = -q \mu_p p \frac{d\phi}{dx} - q D_p \frac{dp}{dx}$$

Einstein relationship

$$\frac{D_n}{\mu_n} = \frac{kT}{q}, \quad \frac{D_p}{\mu_p} = \frac{kT}{q}$$

Current in semiconductor

Electron and hole current density (Drift + diffusion)

$$J_n = -q \mu_n n \frac{d\phi}{dx} + q D_n \frac{dn}{dx} \quad J_p = -q \mu_p p \frac{d\phi}{dx} - q D_p \frac{dp}{dx}$$

Total current in semiconductor

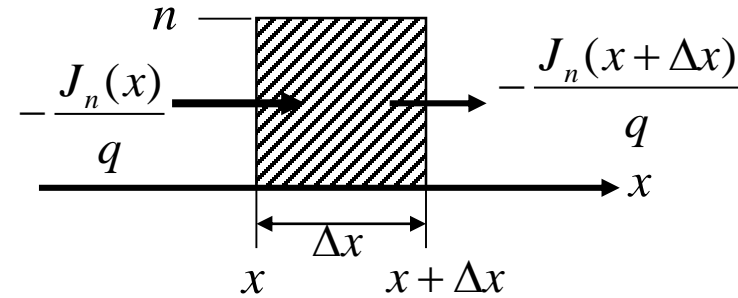
$$J = J_n + J_p + J_{disp}$$

$$J_{disp} = \frac{d\epsilon E}{dt}$$

Displacement current

Current continuity equation

Continuity equations for electron current and hole current



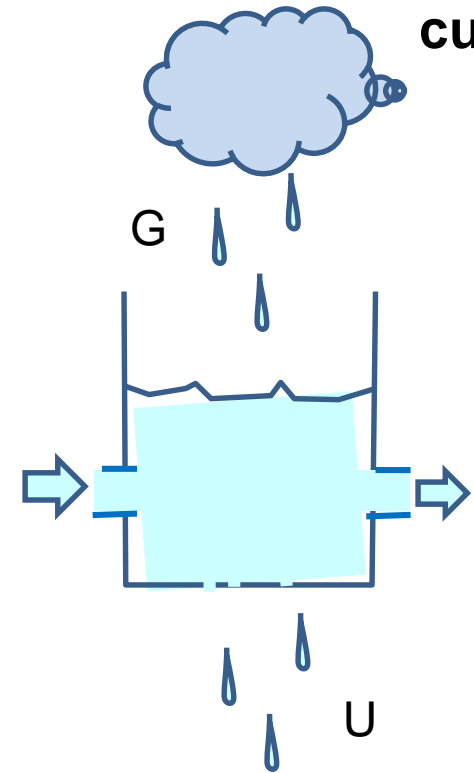
$$\frac{dn}{dt} \Delta x = -\frac{J_n(x)}{q} + \frac{J_n(x + \Delta x)}{q} + G_n \cdot \Delta x - U_n \cdot \Delta x$$

Gauss' Theorem

G_p, G_n : carrier generation rate [Carriers/cm³/sec]
 U_n, U_p : carrier recombination rate [Carriers/cm³/sec]

Current continuity equation

Continuity equations for electron current and hole current



$$\frac{dn}{dt} \Delta x = -\frac{J_n(x)}{q} + \frac{J_n(x + \Delta x)}{q} + G_n \cdot \Delta x - U_n \cdot \Delta x$$

↓ $\Delta t \rightarrow \text{zero}$

$$\frac{dn}{dt} = \frac{1}{q} \frac{dJ_n}{dx} + G_n - U_n$$

$$\frac{dp}{dt} = -\frac{1}{q} \frac{dJ_p}{dx} + G_p - U_p$$

G_p, G_n : carrier generation rate [Carriers/cm³/sec]

U_n, U_p : carrier recombination rate [Carriers/cm³/sec]

Poisson eq. and Donor / acceptor

Poisson equation:

Equation to obtain electric field

$$\frac{d\varepsilon \cdot E}{dx} = \rho$$

Poisson eq.

$$\frac{d\varepsilon \cdot E}{dx} = q(N_D - N_A + p - n)$$

Charge density [C/cm³]

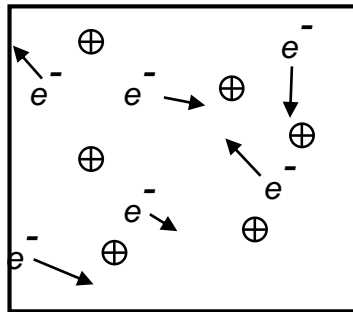
where

$$E = -\frac{d\phi}{dx}$$

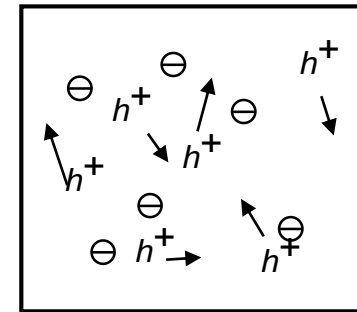
Donor concentration

Acceptor concentration

Free electron and fixed positive charge (Donor) (N_D)



Free hole and fixed negative charge (Acceptor) (N_A)



.....under equilibrium condition

Quasi Fermi Potentials

Expand the Fermi Potential to Non-thermal-equilibrium conditions

Electron quasi Fermi potential ϕ_n

$$n = n_i \cdot e^{\frac{q}{kT}(\phi - \phi_n)}$$

Hole quasi Fermi potential ϕ_p

$$p = n_i \cdot e^{\frac{q}{kT}(\phi_p - \phi)}$$

Under thermal equilibrium condition $\phi_n = \phi_p$

Current equation for electron and hole can be expressed by quasi Fermi potentials (Problem → prove this, use “Einstein relationship”, see next page)

$$J_n = -q \mu_n n \frac{d\phi_n}{dx}$$

$$J_p = -q \mu_p p \frac{d\phi_p}{dx}$$

Problem

$$n = n_i \cdot e^{\frac{q}{kT}(\phi - \phi_n)} \quad p = n_i \cdot e^{\frac{q}{kT}(\phi_p - \phi)}$$

$$J_n = -q \mu_n n \frac{d\phi}{dx} + q D_n \frac{dn}{dx} \quad J_p = -q \mu_p p \frac{d\phi}{dx} - q D_p \frac{dp}{dx}$$

Einstein relationship $\frac{D_n}{\mu_n} = \frac{kT}{q}, \quad \frac{D_p}{\mu_p} = \frac{kT}{q}$



Prove following eq.

$$J_n = -q \mu_n n \frac{d\phi_n}{dx} \quad J_p = -q \mu_p p \frac{d\phi_p}{dx}$$

Summary of basic equations

Equations used in power semiconductor device design

Current equations

$$J_n = -q \mu_n n \frac{d\phi}{dx} + q D_n \frac{dn}{dx} \quad J_p = -q \mu_p p \frac{d\phi}{dx} - q D_p \frac{dp}{dx}$$

Current continuity equations

$$\frac{dn}{dt} = \frac{1}{q} \frac{dJ_n}{dx} + G_n - U_n \quad \frac{dp}{dt} = -\frac{1}{q} \frac{dJ_p}{dx} + G_p - U_p$$

Poisson equation

$$\frac{d \varepsilon \cdot E}{dx} = q(N_D - N_A + p - n) \quad \text{where } E = -\frac{d\phi}{dx}$$

No band theory, no electron energy=>For device design use

Problem: Where is bandgap parameter in the equations??

Related equations

Einstein relationship

$$\frac{D_n}{\mu_n} = \frac{kT}{q}, \quad \frac{D_p}{\mu_p} = \frac{kT}{q}$$

Displacement current and total current

$$J_{disp} = \frac{d\epsilon E}{dt}$$

$$J = J_n + J_p + J_{disp}$$

Carrier density and current density by quasi Fermi potential

$$n = n_i \cdot e^{\frac{q}{kT}(\phi - \phi_n)}$$

$$p = n_i \cdot e^{\frac{q}{kT}(\phi_p - \phi)}$$

$$J_n = -q \mu_n n \frac{d\phi_n}{dx}$$

$$J_p = -q \mu_p p \frac{d\phi_p}{dx}$$

Potentials at Ohmic contact

Metal contact (Ohmic)

Rem.

Under thermal equilibrium condition,

$$\frac{d \varepsilon \cdot E}{dx} = q(N_D - N_A + p - n) = 0$$



$$\begin{cases} N_D - N_A + p - n = 0 \\ p \cdot n = n_i^2 \end{cases}$$

Need to solve equations for accurate hole, electron concentration and built-in potentials

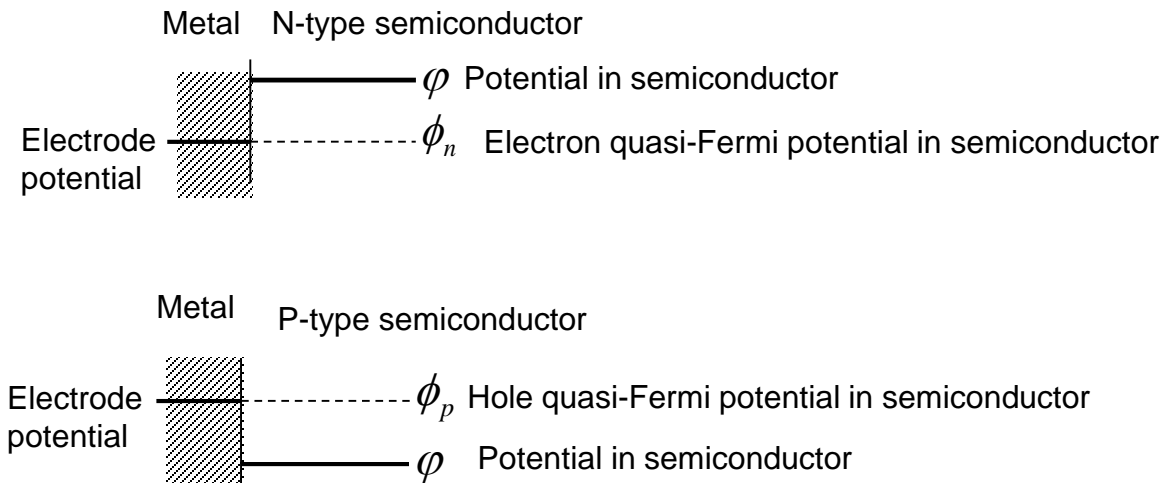
Built-in potential

$$N_D \approx n = n_i e^{\frac{q}{kT}(\phi - \phi_n)}$$

$$V_{built-in} = \frac{kT}{q} \log \frac{N_D}{n_i}$$

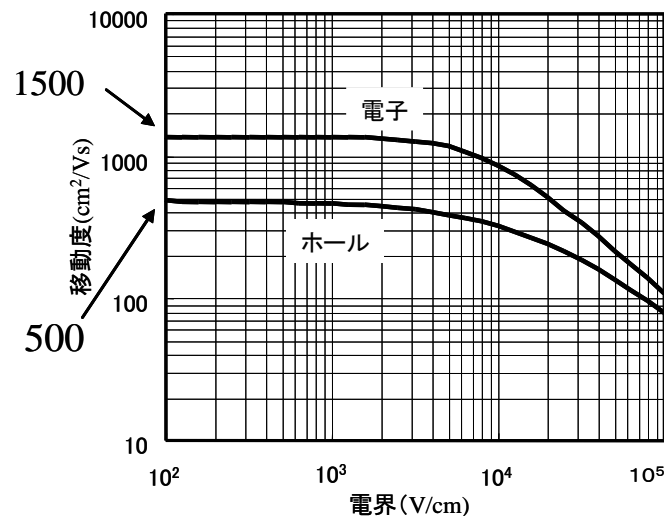
$$N_A \approx p = n_i e^{\frac{q}{kT}(\phi_p - \phi)}$$

$$V_{built-in} = -\frac{kT}{q} \log \frac{N_A}{n_i}$$

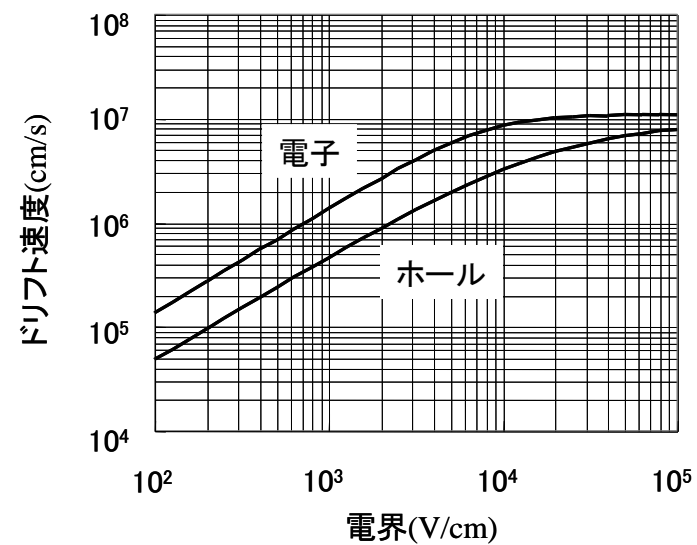


Electron and hole mobility for silicon

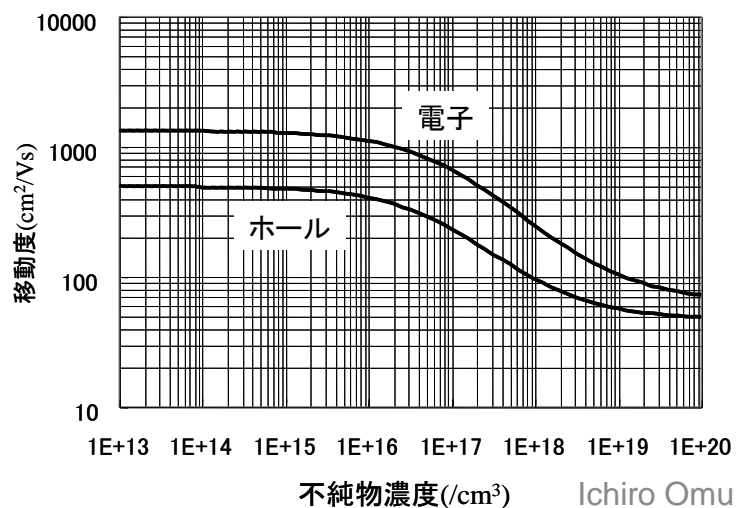
Electron and hole mobility for silicon



Electron and hole velocity for silicon

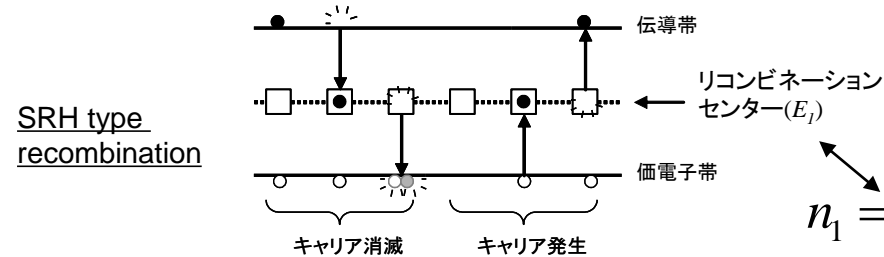


Mobilities as functions of impurity concentration



Recombination (SRH)

Recombination rate U_n, U_p



$$\frac{dn}{dt} = -\frac{1}{q} \frac{dJ_n}{dx} + G_n - U_n$$

$$\frac{dp}{dt} = \frac{1}{q} \frac{dJ_p}{dx} + G_p - U_p$$

$$n_1 = n_i e^{(E_i - E_i)/kT}$$

$$p_1 = n_i e^{(E_i - E_i)/kT}$$

Electron and hole lifetime

$$U_n^{SRH} = U_p^{SRH} = \frac{pn - n_i^2}{\tau_p(n + n_1) + \tau_n(p + p_1)}$$

In N-type semiconductor ($n = N_D \gg p$)

$$U_n^{SRH} = U_p^{SRH} = \frac{p - p_{n0}}{\tau_p}$$

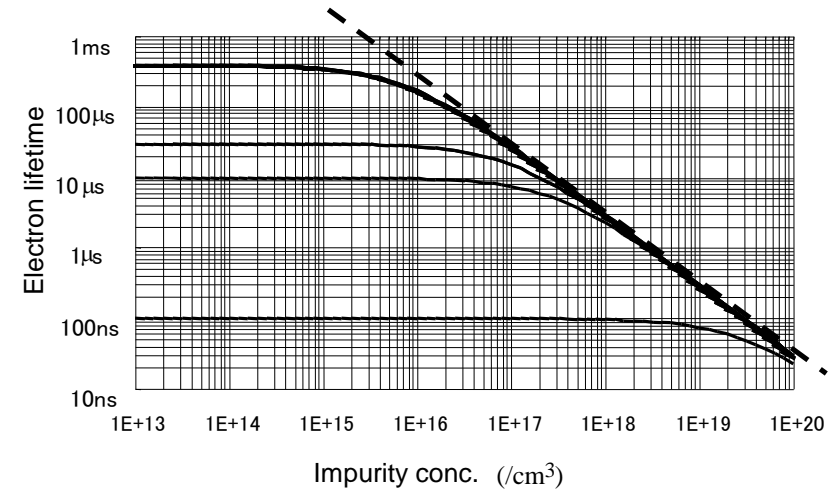
In P-type semiconductor ($p = N_A \gg n$)

$$U_n^{SRH} = U_p^{SRH} \cong \frac{n - n_{p0}}{\tau_n}$$

p_{n0} : hole density in N-type semiconductor

n_{p0} : electron density in P-type semiconductor

Carrier lifetime lowering by impurity



Impact ionization

Carrier generation / impact ionization

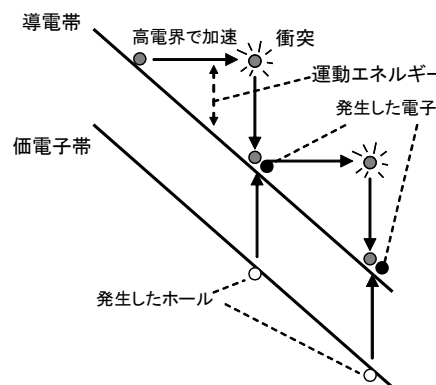
Ionization rate

$$\alpha_n(E) = A_n e^{-b_n/|E|}$$

$$\alpha_p(E) = A_p e^{-b_p/|E|}$$

Carrier generation rate by impact ionization

$$G_n^{imp} = G_p^{imp} = \frac{1}{q} \left(\alpha_n |J_n| + \alpha_p |J_p| \right)$$



Example of parameters

$$A_n = 7.03 \times 10^5 [\text{cm}^{-1}]$$

$$A_p = 1.582 \times 10^6 [\text{cm}^{-1}]$$

$$b_n = 1.23 \times 10^6 [\text{V/cm}]$$

$$b_p = 2.036 \times 10^6 [\text{V/cm}]$$

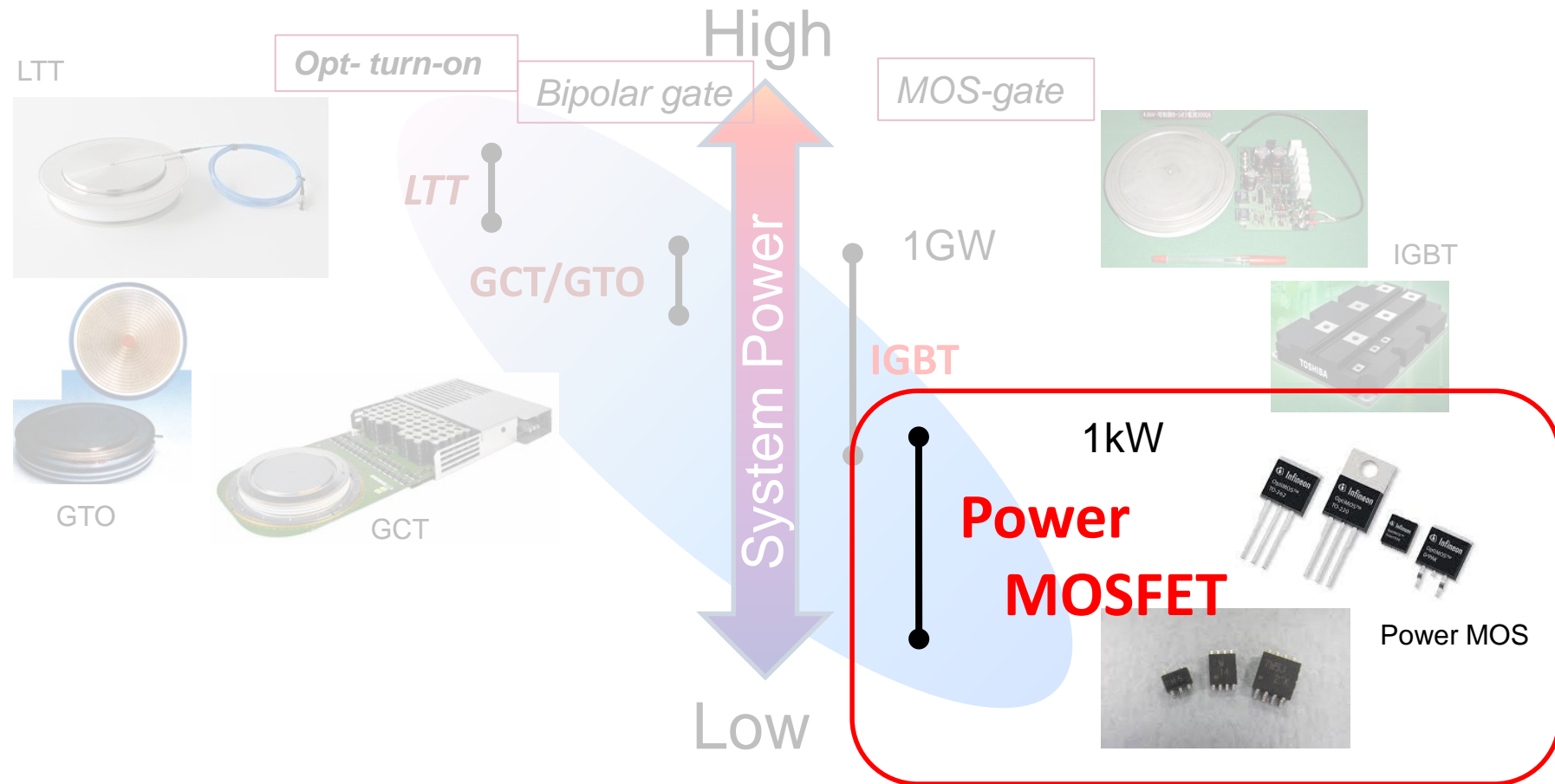
$$\frac{dn}{dt} = -\frac{1}{q} \frac{dJ_n}{dx} + \boxed{G_n} - U_n$$

$$\frac{dp}{dt} = \frac{1}{q} \frac{dJ_p}{dx} + \boxed{G_p} - U_p$$

Ionization rate: number of electron-hole pairs generated by moving electron or holes for 1cm

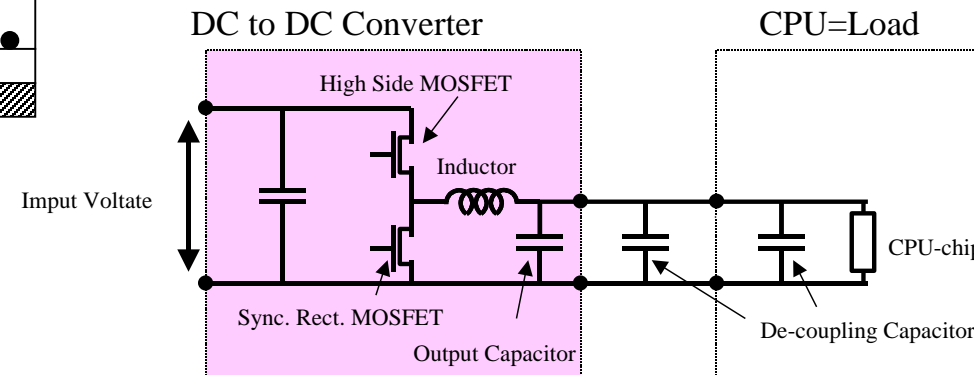
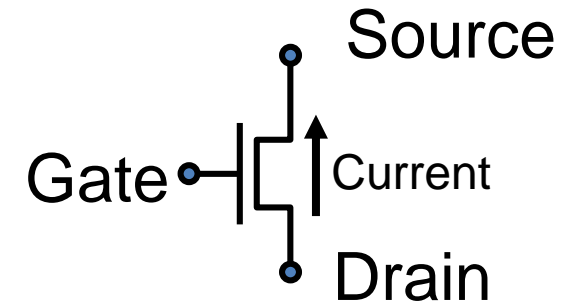
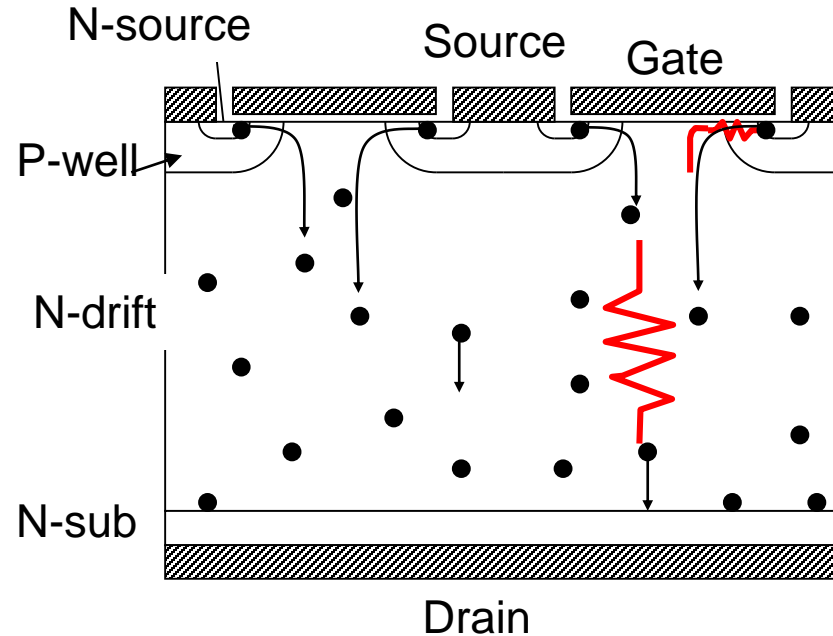
Carrier generation rate: number of electron-hole pairs generated in 1 cm³ for 1 sec.

Power MOSFET



Photos:
Infineon
Toshiba
ABB
TMEIC

Power MOSFET

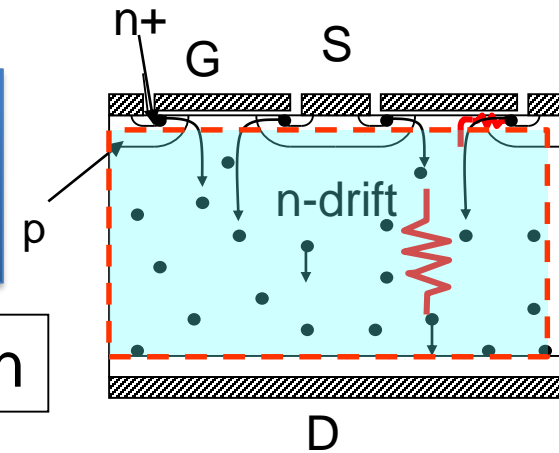


Conduction carrier..... *Electron or hole*
 Switching control *MOS-gate*
 Switching Freq. *High*

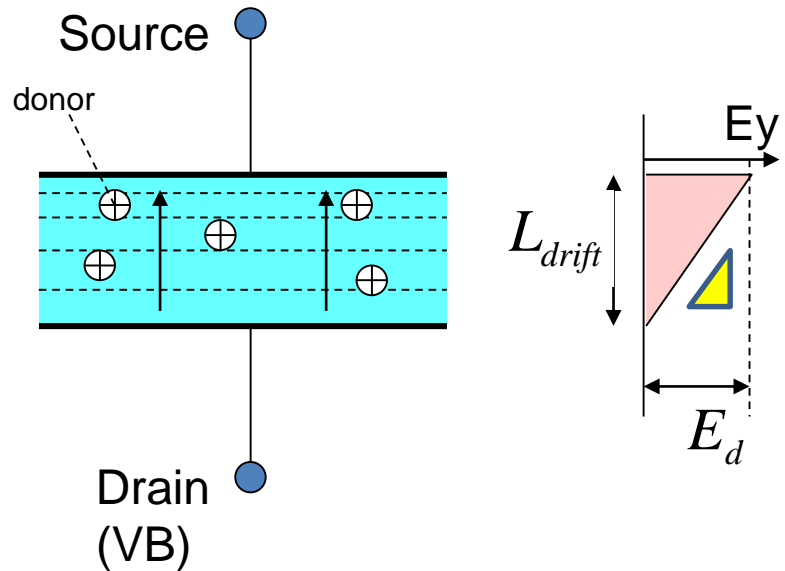
Function of N-drift layer

Function of N-drift layer:

1. Voltage blocking (higher breakdown voltage)
2. Current conduction (lower resistivity)



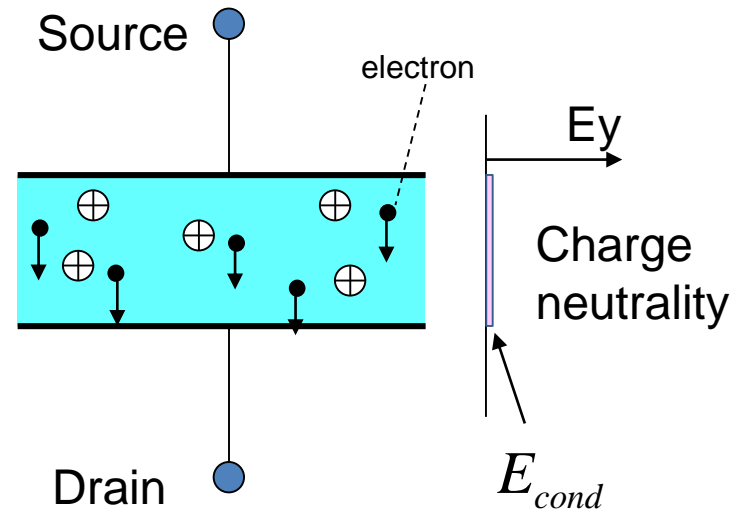
Voltage Blocking



Blocking state (Poisson eq.)

$$qN_D = -\epsilon \frac{dE_y}{dy} = \epsilon \cdot \frac{E_d}{L_{drift}}$$

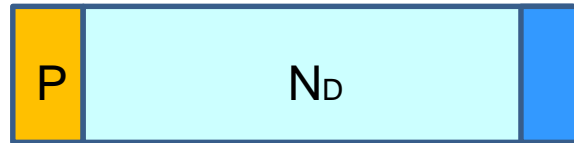
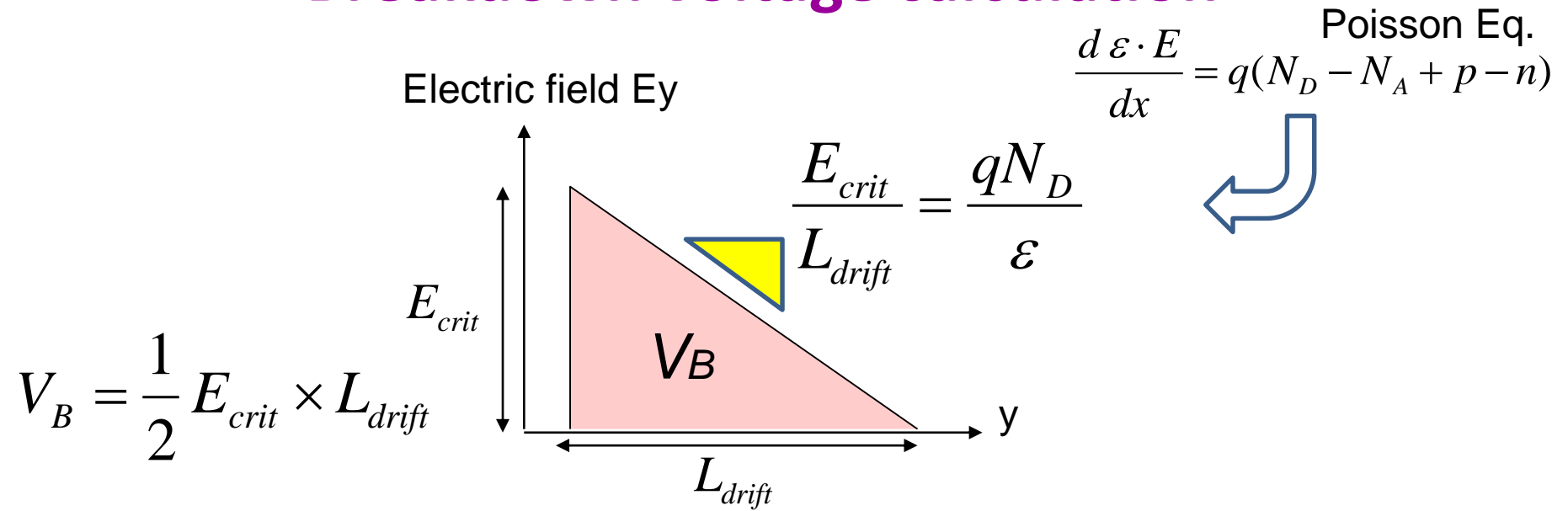
Conduction



Conduction state (current eq.)

$$J_n = q\mu_n N_D E_{cond} = q\mu_n N_D \frac{V_{cond}}{L_{drift}}$$

Breakdown voltage calculation



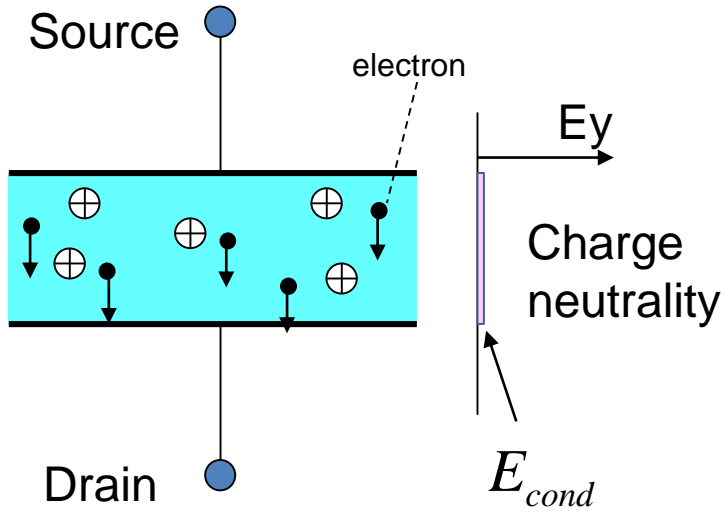
Drift layer doping

$$N_D = \varepsilon \cdot \frac{E_{crit}^2}{2qV_B}$$

Drift layer length

$$L_{drift} = \frac{2V_B}{E_{crit}}$$

Conduction resistance calculation



Conduction resistance

$$J_n = q\mu_n N_D E_{cond} = q\mu_n N_D \frac{V_{cond}}{L_{drift}}$$

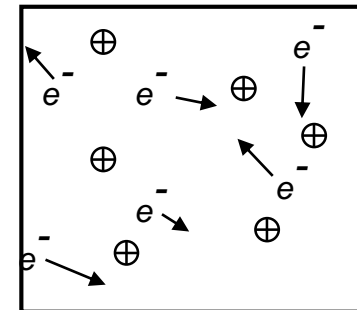
$$R_{on} A = \frac{L_{drift}}{q\mu_n N_D} \quad \text{Resistance for unit area}$$

$$\frac{d \varepsilon \cdot E}{dx} = q(N_D - N_A + p - n) \approx 0$$



$$n \approx N_D$$

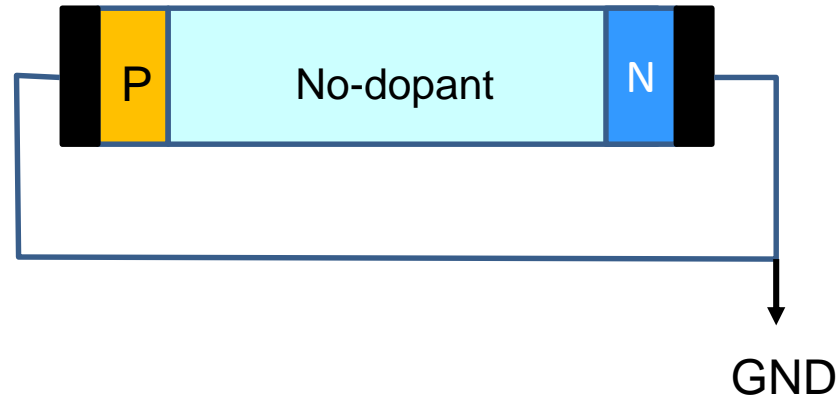
Free electron and fixed positive charge (Donor) (N_D)



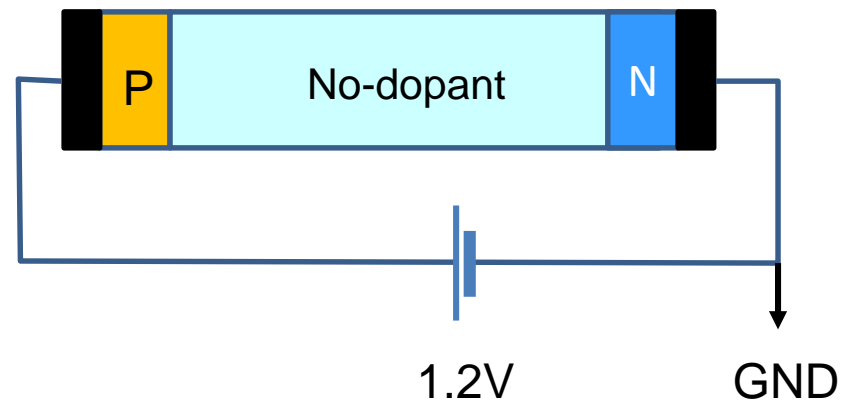
Problem

1. Calculate required drift length for breakdown voltage 1200V.
($E_{crit}=2.0E5$ V/cm)
2. Calculate donor concentration for drift layer
($q=1.6E-19$ C, $\epsilon=1.0e-12$ [F/cm](silicon))
3. Calculate drift resistance (mobility of electron 1500 cm²/V-s)
4. Calculate 1~3 for 600V, 1700V,

Problem: Draw potential distribution in PiN diode and electrode



Problem: Draw potential distribution in PiN diode, assume constant stored carrier n_{store}



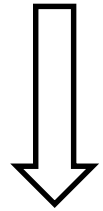
Not to be used in the lecture

Boltzmann Approximation

Electron

$$n = \int_{E_c}^{\infty} e^{-(E-E_F)/kT} N(E) dE$$

$$= e^{-(E_C-E_F)/kT} \int_{E_c}^{\infty} e^{-(E-E_C)/kT} N(E) dE$$



N_C

Effective Density of State

$$n = N_C \cdot e^{-(E_C-E_F)/kT}$$

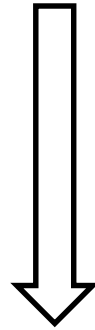
Boltzmann Approximation

Hole

Fermi-Dirac
distribution

Density of
state

$$p = \int_{-\infty}^{E_V} \left\{ 1 - \frac{1}{1 + e^{(E - E_F)/kT}} \right\} N(E) dE$$



$$1 - \frac{1}{1 + e^{(E - E_F)/kT}} \approx e^{(E - E_F)/kT}$$

$$p = N_V \cdot e^{-(E_F - E_V)/kT}$$

$$\begin{aligned} p &= \int_{-\infty}^{E_V} \left\{ 1 - \frac{1}{1 + e^{(E - E_F)/kT}} \right\} N(E) dE \\ &\cong \int_{-\infty}^{E_V} e^{(E - E_F)/kT} N(E) dE \\ &= e^{(E_V - E_F)/kT} \int_{-\infty}^{E_V} e^{(E - E_V)/kT} N(E) dE \end{aligned}$$

Effective Density of State

N_V

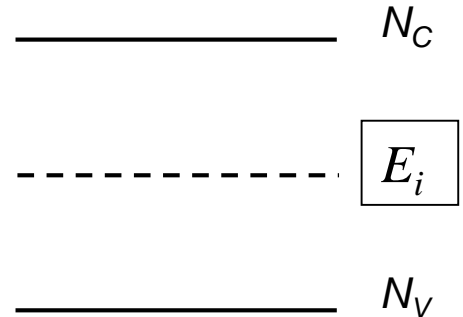
Intrinsic carrier density, n_i

Pure semiconductor without impurity = Intrinsic semiconductor

Charge neutrality under thermal equilibrium $\rightarrow p = n = n_i$

$$n_i = N_C \cdot e^{-(E_C - E_i)/kT} \quad \text{Electron density}$$

$$n_i = N_V \cdot e^{-(E_i - E_V)/kT} \quad \text{Hole density}$$

$$\begin{aligned} n_i &= \sqrt{N_C \cdot N_V} e^{-(E_C - E_V)/2kT} \\ &= \sqrt{N_C \cdot N_V} e^{-E_g/2kT} \end{aligned}$$


The diagram shows three horizontal lines representing energy levels. The top solid line is labeled N_C on the right. The bottom solid line is labeled N_V on the right. A dashed line is positioned between the two solid lines and is labeled E_i on the right, enclosed in a box.

Problem: Calculate intrinsic Fermi level, E_i

Intrinsic carrier density and potentials

$$n = N_C \cdot e^{-(E_C - E_F)/kT}$$

$$p = N_V \cdot e^{-(E_F - E_V)/kT}$$

$$n_i = N_C \cdot e^{-(E_C - E_i)/kT}$$

$$n_i = N_V \cdot e^{-(E_i - E_V)/kT}$$

$$n = n_i \cdot e^{(E_F - E_i)/kT}$$

$$p = n_i \cdot e^{(E_i - E_F)/kT}$$

$$\text{Potential } \varphi = -\frac{E_i}{q} \quad \text{Fermi Potential } \phi = -\frac{E_F}{q}$$

$$n = n_i \cdot e^{\frac{q}{kT}(\varphi - \phi)}$$

$$p = n_i \cdot e^{\frac{q}{kT}(\phi - \varphi)}$$

Thermal equilibrium condition

$$\text{Potential[V]} \quad \varphi = -\frac{E_i}{q} \quad \text{Fermi Potential[V]} \quad \phi = -\frac{E_F}{q}$$

$$n = n_i \cdot e^{\frac{q}{kT}(\varphi - \phi)} \quad p = n_i \cdot e^{\frac{q}{kT}(\phi - \varphi)}$$

$$p \cdot n = n_i^2$$

$$[\text{H}^+] \times [\text{OH}^-] = 1 \times 10^{-14} (\text{mol/L})^2$$

Boltzmann Approximation (Appdx)

Electron

$$n = \int_{E_c}^{\infty} e^{-(E-E_F)/kT} N(E) dE$$

Hole

$$p = \int_{-\infty}^{E_v} e^{(E-E_F)/kT} N(E) dE$$

$$pn = \int_{E_c}^{\infty} e^{-(E-E_F)/kT} N(E) dE \times \int_{-\infty}^{E_v} e^{(E-E_F)/kT} N(E) dE = \text{Constant for any } E_F$$

Define intrinsic carrier density n_i as,

$$n_i = \sqrt{\int_{E_c}^{\infty} e^{-(E-E_F)/kT} N(E) dE \times \int_{-\infty}^{E_v} e^{(E-E_F)/kT} N(E) dE} \longrightarrow p \cdot n = n_i^2$$

E_i is defined so that following equation is satisfied ($p=n=n_i$ for pure crystal from Poisson Eq.).

$$n_i = \int_{E_c}^{\infty} e^{-(E-E_i)/kT} N(E) dE = \int_{-\infty}^{E_v} e^{(E-E_i)/kT} N(E) dE$$

$$n = n_i \cdot e^{(E_F-E_i)/kT} \qquad p = n_i \cdot e^{(E_i-E_F)/kT}$$